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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10085903	02 28 2002	257		2875	

**APPLICANTS: Wei Andy Sultan Akif Wu David

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed		<input type="checkbox"/> yes <input checked="" type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met		<input type="checkbox"/> yes <input checked="" type="checkbox"/> no	AMDI.115 HON
Verified and Acknowledged Examiner's initials			
TITLE : SOI mosfet junction degradation using multiple buried amorphous layers			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED											
		<table border="1"> <tr> <td>Total Claims</td> <td>Print Claim for O.G</td> </tr> </table>			Total Claims	Print Claim for O.G							
Total Claims	Print Claim for O.G												
ISSUE FEE		DRAWING											
Amount Due	Date Paid	<table border="1"> <tr> <td>Sheets Drwg.</td> <td>Figs.Drwg.</td> <td>Print Fig.</td> </tr> </table>			Sheets Drwg.	Figs.Drwg.	Print Fig.						
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TERMINAL DISCLAIMER		<table border="1"> <tr> <td colspan="3">Primary Examiner</td> </tr> <tr> <td colspan="3">PREPARED FOR ISSUE</td> </tr> <tr> <td colspan="3">Application Examiner</td> </tr> </table>			Primary Examiner			PREPARED FOR ISSUE			Application Examiner		
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PREPARED FOR ISSUE													
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